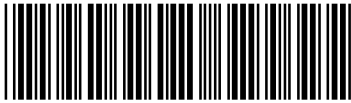


Search Notes

Application/Control No.

10/743,787

Examiner

MICHAEL Y. WON

Applicant(s)/Patent under
Reexamination

MAEDA, TOSHIHIRO

Art Unit

2455

SEARCHED

| Class | Subclass | Date | Examiner |
|-------|-----------------------|-----------|----------|
| 709 | 221, 222, 223, 228 | 5/13/2010 | MW |
| 715 | 736, 853 | 5/13/2010 | MW |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
|-------|----------|-----------|----------|
| 709 | 223 | 5/13/2010 | MW |
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
|---|-----------|------|
| EAST: USPAT; USPG-PUB; DERWENT; EPO; JPO | 5/13/2010 | MW |
| NPL SEARCH: IEEE | 5/13/2010 | MW |
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